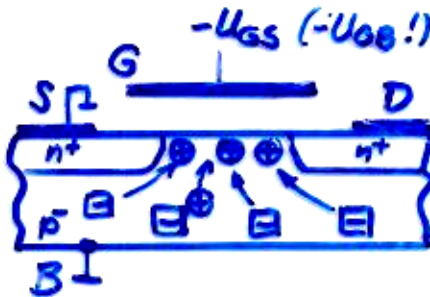


(MOS)

MIS - Leitungsvorgang (n-Kanal)

①

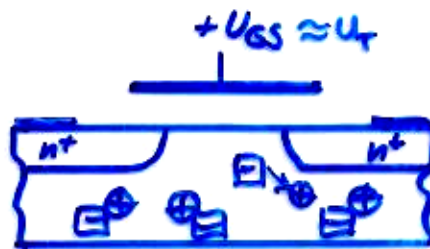


Kanal anreicherung
von Defektelektronen

$$-U_{GS}$$

⊕: Defektelektronen
⊖: ortsfeste Akzeptoren

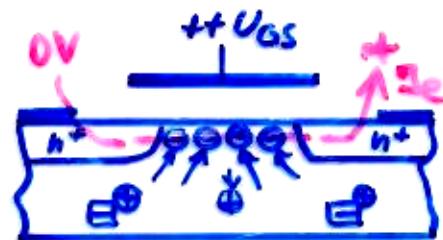
②



Entblöpfung
an bewegl. Ladungstr.

$$0 < U_{GS} < U_T$$

③

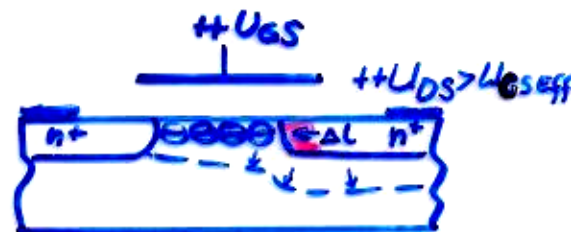


Kanal inversion
von entblöhten
Elektronen

$$U_{GS} > U_T$$

$$U_{GS} - U_T > U_{DS}$$

④

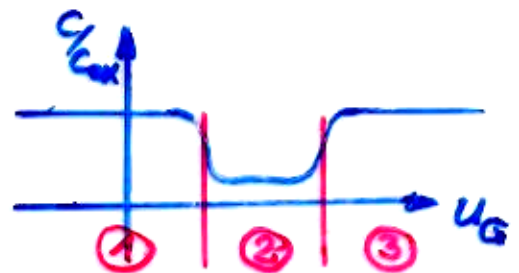


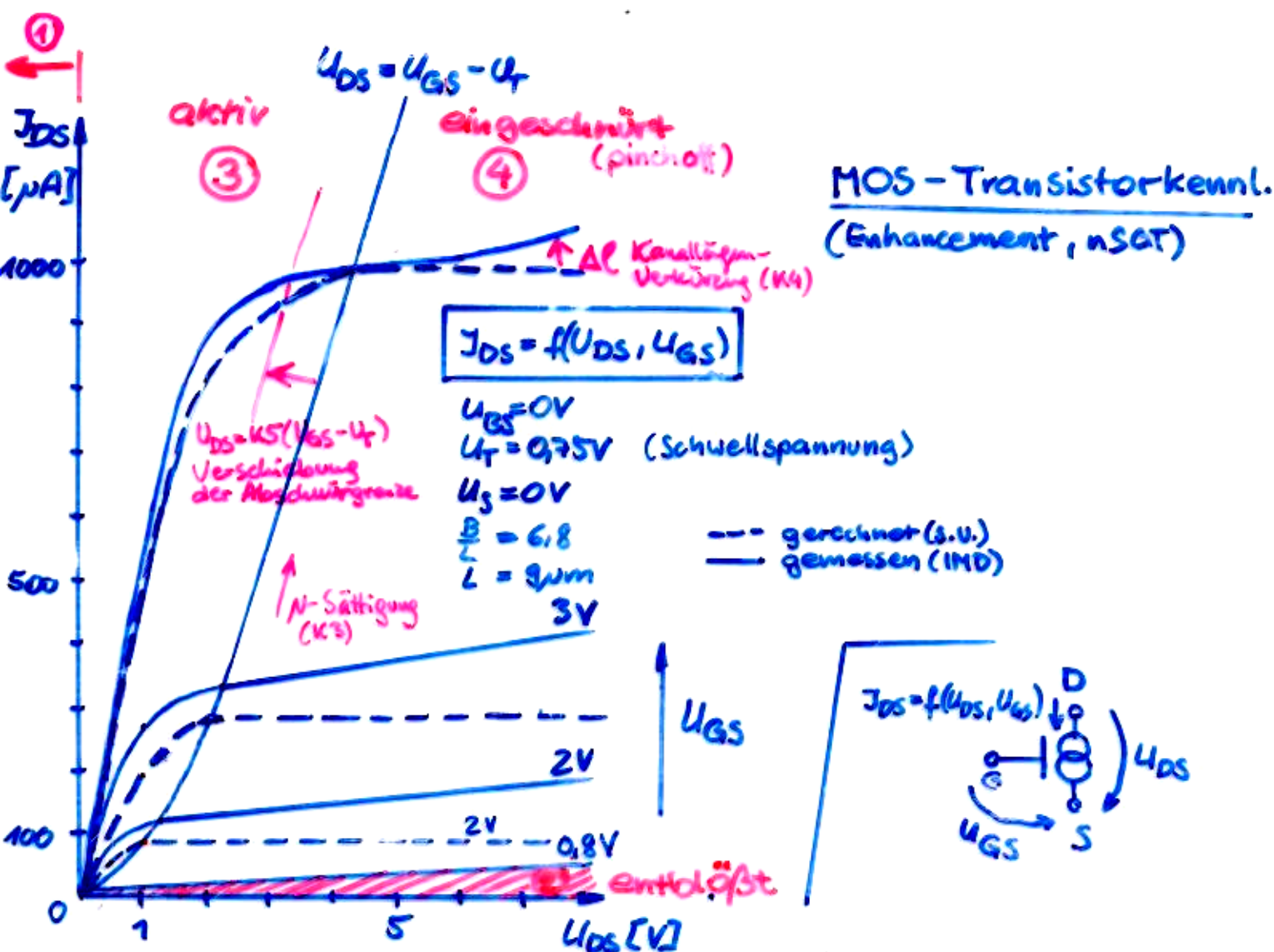
Kanallängen-
verkürzung ΔL ,
Aufweitung $n^+ RL$

$$U_{GS} > U_T$$

$$U_{GS} - U_T < U_{DS}$$

→ spannungsabhängige Gatekapazität:





Transistormodell: Kennlinienappr. (vereinfacht, ohne ΔL !) E + D !

gesperrt: ①② $0 < U_{GS} < U_T$; $I_{DS} = 0$

aktiv: ③ $U_{DS} \leq U_{GS} - U_T$

$$I_{DS} = \beta_0 \frac{b}{L} \left((U_{GS} - U_T) U_{DS} - \frac{1}{2} U_{DS}^2 \right) \rightarrow I_{DS} \sim \frac{b}{L} f(U_{GS}, U_{DS})$$

eingeschnürt: ④ $U_{DS} > U_{GS} - U_T$

$$I_{DS} = \frac{1}{2} \beta_0 \frac{b}{L} (U_{GS} - U_T)^2$$

$$\rightarrow I_{DS} \sim \frac{b}{L} \cdot U_{GSE}^2$$

$$\beta_0 = \mu \cdot C_{ox}'' = \mu \cdot \frac{\epsilon_{ox}}{d_{ox}} \approx 12 \dots 20 \frac{\mu A}{V^2} \text{ (nSGT)}$$

$$\uparrow \left[\frac{cm^2}{Vs} \right]$$

$$U_T = f(U_{BS}): \text{ (Transferegate ss)}$$

$$U_T = U_{T0} + K_1 (\sqrt{U_{BS} + 2V_F} - \sqrt{2V_F})$$

$$U_{T0} \approx U_T(U_{BS}=0) \text{ (0,75V)}$$

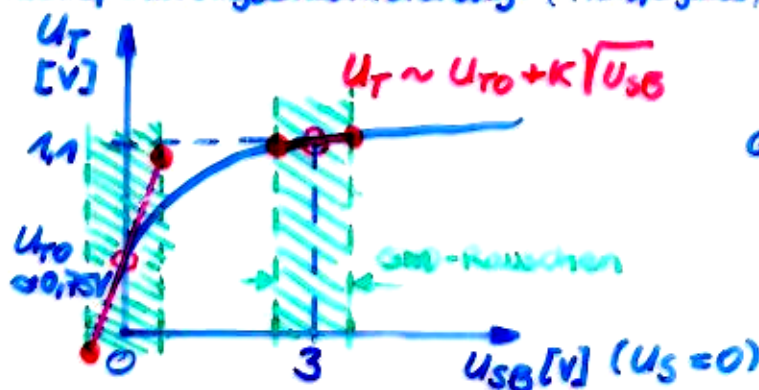
$$K_1: \text{ Substratrückwirkungskonstante (0,31)}$$

$$V_F: \text{ Fermipotential (0,64V)}$$

$$U_{TD} = \begin{cases} -3,5 & (U_{BS}=0) \\ -3,45 & (U_{BS}=-3) \\ -3,0 & (U_{BS}=-5) \end{cases}$$

$$U_{TE} = \begin{cases} 0,75 & (U_{BS}=0V) \\ 1,1 & (U_{BS}=-3V) \\ 1,23 & (U_{BS}=-5V) \end{cases}$$

Schwellspannungsstabilisierung: (Transferegate, dyn. Speicher etc)



praktisch: ($U_{BS} = 3V$)

$$E: U_{TDE} \approx 0,75V$$

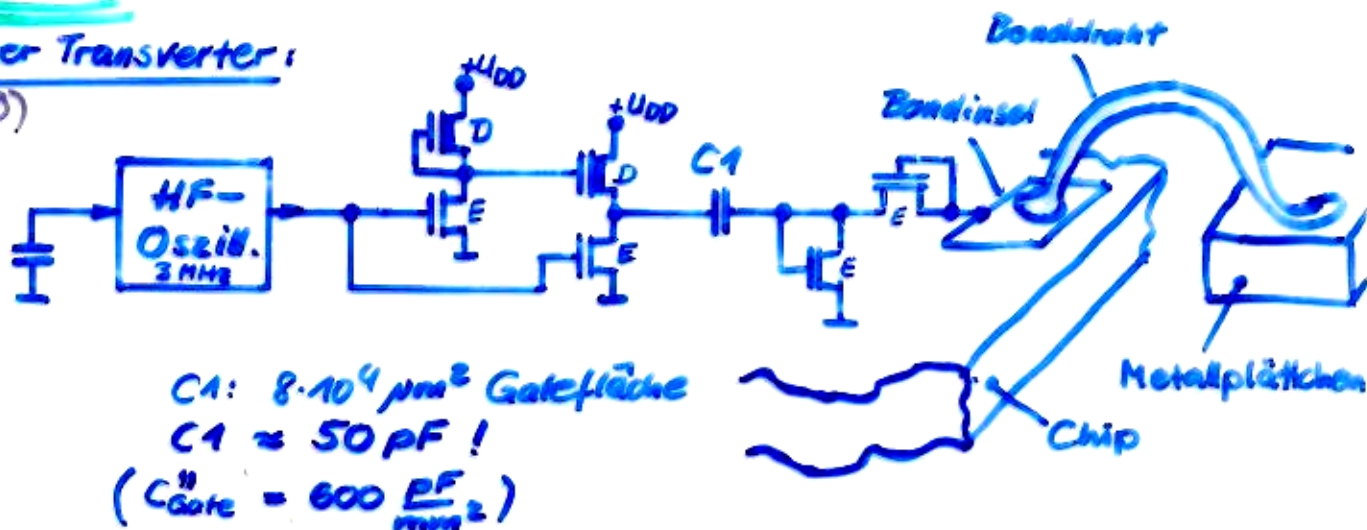
$$U_T \approx 1V$$

$$D: U_{TDD} \approx -3,5V$$

$$U_T \approx -3V$$

Ziel: $\frac{dU_T}{dU_{BS}} \rightarrow \text{MIN.}$ + $C_{Sperr} \rightarrow \text{MIN.}$: Verringerung um ca. 30% (!) bei $U_{BS} = 3V$

3C-interner Transverter:
(8279)

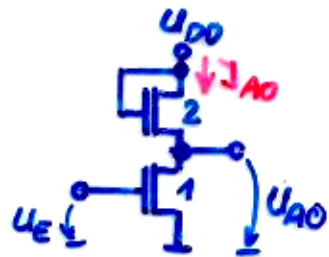


$$U_{SB} \approx U_{DD} - 2U_{TE} \approx 3V.$$

$$\text{Circuit symbol} \hat{=} \text{Circuit symbol} (U_{AKF} \approx U_T)$$

EE-Inverter: statische Dimensionierung:

$$\gamma = f(U_{AO}, U_{EH})$$



$$\begin{aligned} U_T &= 1,1V \\ (U_{BS} &= -3V) \\ U_{DD} &= 5V \\ U_{AO} &= 0,38V \\ \beta_{01} &= 9,016 \frac{mA}{V^2} \end{aligned}$$

$$\begin{cases} I_{DS2} = \frac{\beta_{02}}{2} \cdot \frac{b_2}{L_2} (U_{GS2} - U_T)^2 \\ I_{DS1} = \beta_{01} \frac{b_1}{L_1} (U_{GS1} - U_T) U_{DS1} - \frac{U_{DS1}^2}{2} \end{cases}$$

$$\gamma = \frac{\frac{b_1}{L_1}}{\frac{b_2}{L_2}} = \frac{(U_{GS2} - U_T)^2}{2((U_{GS1} - U_T) U_{DS1} - \frac{U_{DS1}^2}{2})} \geq 6,3$$

Ruhestrom:

$$I_{AO} = \frac{\beta_{02}}{2} (U_{GS2} - U_{TD})^2 \cdot \frac{b_2}{L_2} = \left(\frac{b}{L}\right)_{last} \cdot 991 \mu A$$

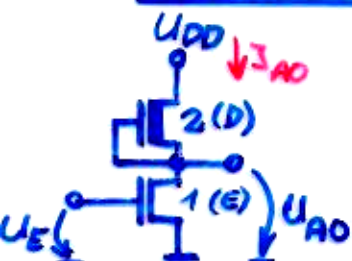
EE-Inverter:

$$\begin{aligned} U_{EH} &= U_{DD} = 5V \\ U_T &= 1,1V \\ U_{AO} &= 0,38V \end{aligned}$$

$$\gamma \geq 6,3$$

$$I_{AO} = \left(\frac{b}{L}\right)_L \cdot 100 \mu A$$

ED-Inverter: statische Dimensionierung:



$$\begin{aligned} U_T &= 1,1V \\ U_{TD} &= -3,15V \\ U_{AO} &= 0,38V \\ \beta_{0D} &= 0,020 \frac{mA}{V^2} \end{aligned}$$

$$\begin{cases} I_{DS2} = \frac{\beta_{0D}}{2} \cdot \frac{b_2}{L_2} \cdot (U_{GS2} - U_{TD})^2 \\ I_{DS1} = \beta_{0E} \frac{b_1}{L_1} (U_{GS1} - U_T) U_{DS1} - \frac{U_{DS1}^2}{2} \end{cases}$$

$$\gamma = \frac{\frac{b_1}{L_1}}{\frac{b_2}{L_2}} = \frac{\beta_{0D} (-U_{TD})^2}{\beta_{0E} 2((U_{GS1} - U_T) U_{DS1} - \frac{U_{DS1}^2}{2})} \geq 4,4$$

Ruhestrom:

$$I_{AO} = \frac{\beta_{0D}}{2} (-U_{TD})^2 \cdot \frac{b_2}{L_2} = \left(\frac{b}{L}\right)_{last} \cdot 992 \mu A$$

ED-Inverter:

$$\begin{aligned} U_{EH} &= U_{DD} = 5V \\ U_T &= 1,1V \\ U_{AO} &= 0,38V \end{aligned}$$

$$\gamma \geq 4,4$$

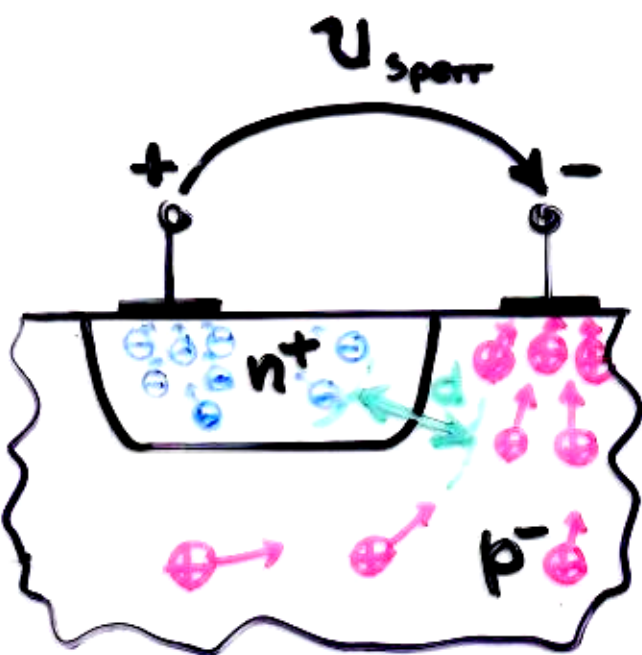
$$I_{AO} = \left(\frac{b}{L}\right)_L \cdot 100 \mu A$$

$$\Rightarrow \gamma = f(U_{DD}, U_T, U_{AO}, U_{EH})$$

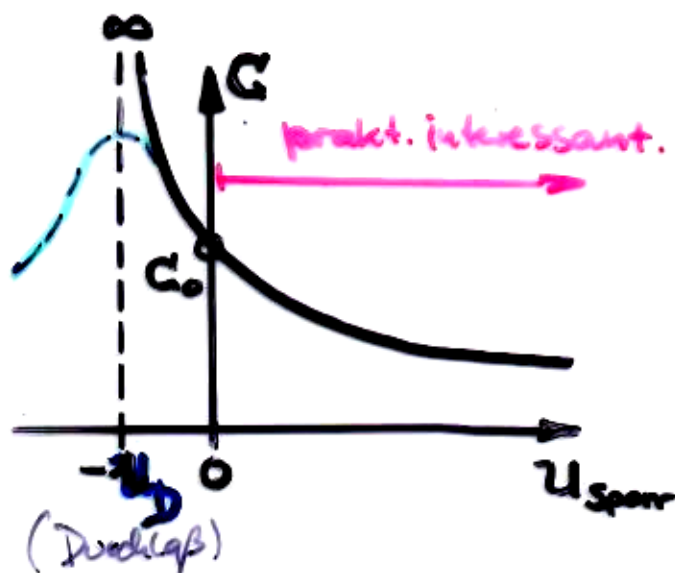
für alle Stufen des IC konst. kritisch bei $U_{EH} = U_{DD} - k \cdot U_T$
dann: $U_A = f(U_E, \gamma)$ -Kennlinie

SPERRSCHICHTKAPAZITÄT

pn-Übergang



$$d = f(U_{sper})$$



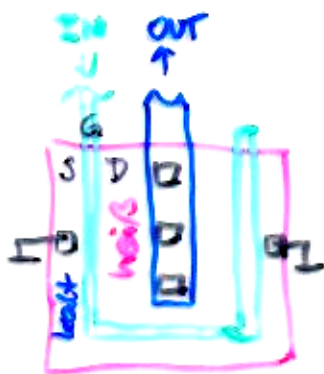
$$C = \frac{C_0}{\sqrt[3 \dots 4]{1 + \frac{U_{sper}}{U_D}}}$$

mit:

$$C_0 = C'' \cdot A \quad (\text{Kanten vernachl.})$$

→ Randgebiete nicht auf Signalleitungen legen!

↳ Layoutgestaltung bei Padtreibern



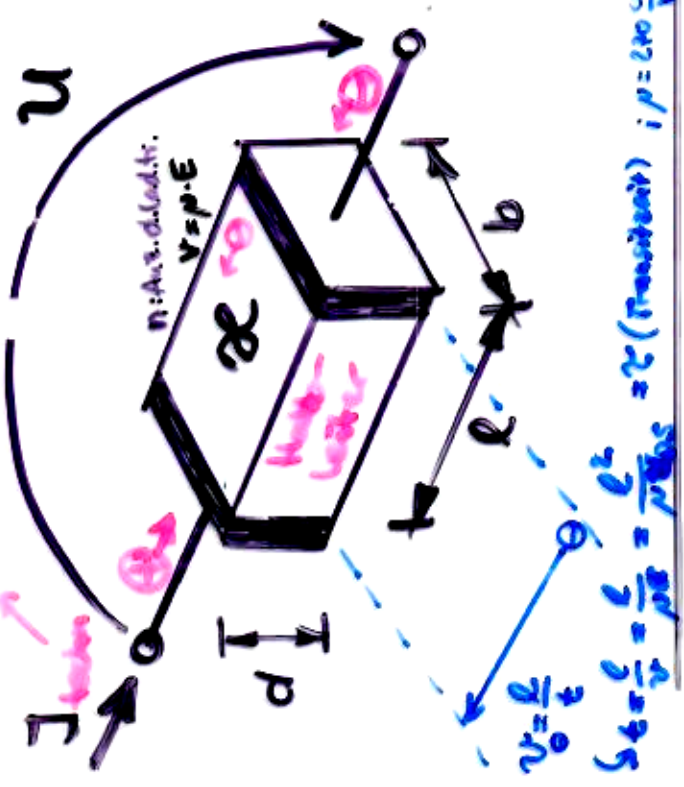
$\rho_{Si} = 3000 \frac{kg}{m^3}$
 $G_{Si} = 450000 \frac{kg}{m^3}$

$\eta_d = f(u_{ds}, u_{gd})$
 (statistisch)

$I \sim U$
 $I = e n d \frac{Q}{t} U_{ds}$

Stat. Dimensionierung

$\mu = \frac{v}{E} \left[\frac{m/s}{V/m} = \frac{m^2}{Vs} \right]$
 $E = \frac{U}{d} \left[\frac{V}{m} \right]$



$\tau = \frac{l}{v} = \frac{l}{\mu E} = \frac{l^2}{\mu U_{ds}} = \tau_c \text{ (Transitzeit)}$
 $\mu = 240 \frac{cm^2}{Vs}$

Grundgleichn:



Energie: $I = Q \cdot T$
 $W = U \cdot Q = U \cdot I \cdot t$
 mit $Q = e$ (Elementarladung)
 $W = e \cdot U \cdot I$ (Elektronen)

$\frac{\Delta U}{\Delta t} = \frac{\Delta Q / \Delta t}{C} = \frac{I}{C}$

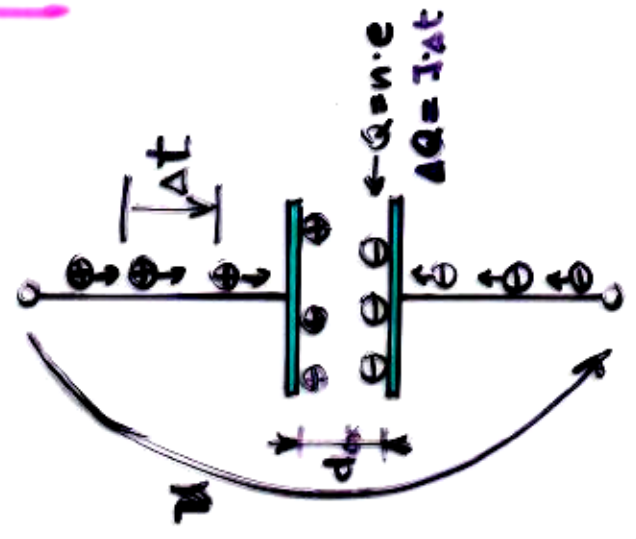
$\frac{\Delta Q}{\Delta U} = C_{const} = C$

$E = \int Q dU = \int C U dU$

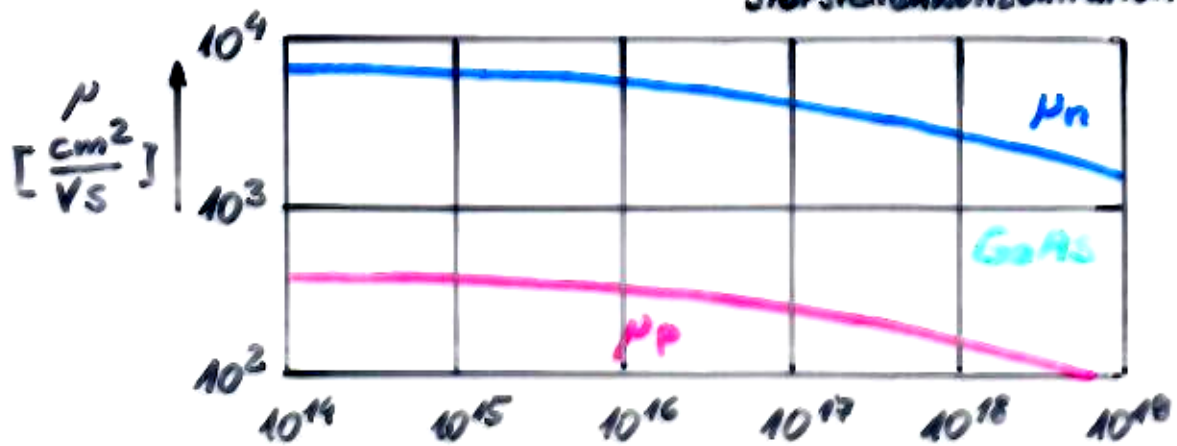
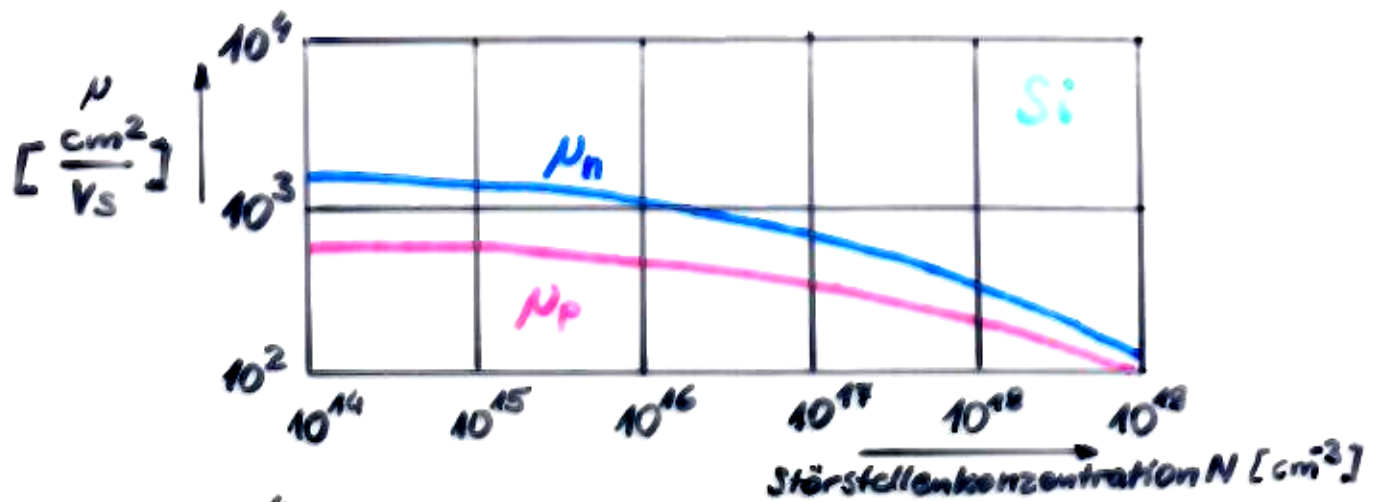
$C \sim \frac{1}{d} \cdot A$

$C = \epsilon \cdot \frac{A}{d}$

$C [pF] = C' \left[\frac{pF}{\mu m^2} \right] \cdot A [\mu m^2]$



Beweglichkeit $\mu \rightarrow \beta_0$



Eigenleitungsdichte n_i

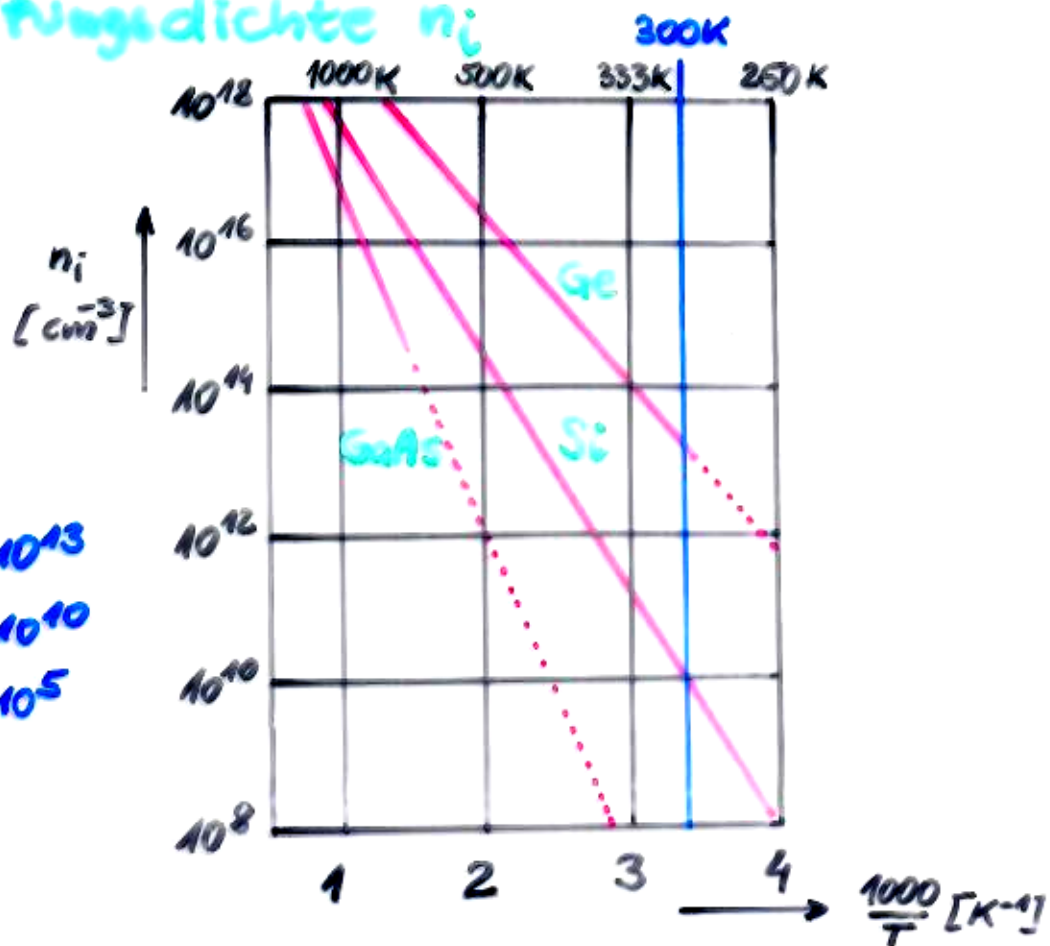
$\hookrightarrow C_{n+p}$

300K:

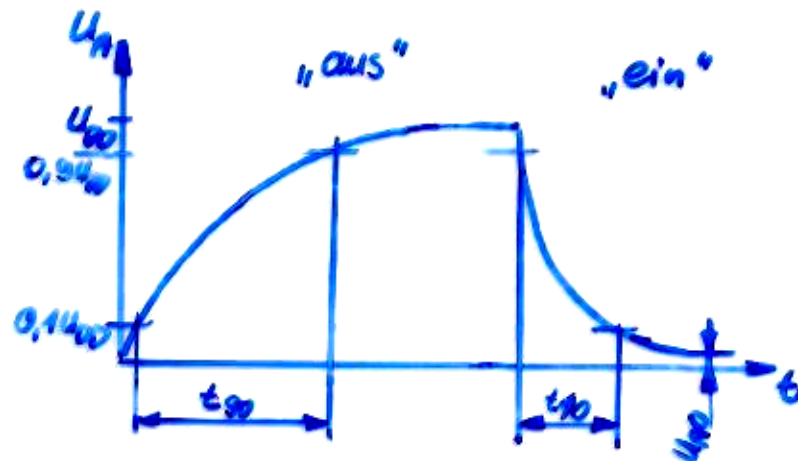
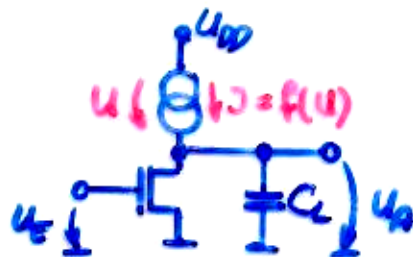
$$n_{i\text{Ge}} = 2 \cdot 10^{13}$$

$$n_{i\text{Si}} = 1,5 \cdot 10^{10}$$

$$n_{i\text{GaAs}} = 5 \cdot 10^5$$

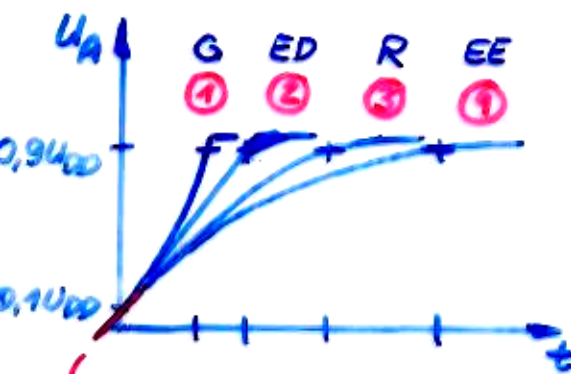


Verzögerungszeiten:



"Einschalten:" $t_{90}/\text{ns} \approx 30 \cdot \frac{C_L/\text{pF}}{(\frac{b}{L})_{\text{Schalt}}}$

"ausschalten:"



$$\left. \frac{dU_A}{dt} \right|_{t=0} = \frac{(\frac{b}{L})_{\text{last}}}{C_L} \cdot J_{A0}$$

unabhängig von ①...④.

① $J \sim \sqrt{U}$ (Gegentaktrivorte-)

$$t_{90}/\text{ns} \approx 59 \frac{C_L/\text{pF}}{(\frac{b}{L})_{\text{last}}} \quad (t_{10} \text{ auch kürzer})$$

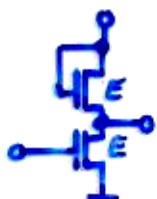
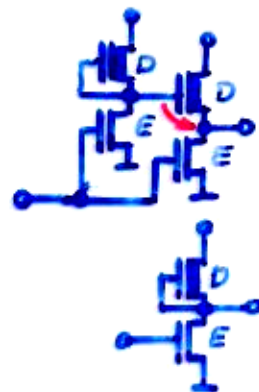
② $J \approx \text{konst.}$ (Depl. Last)

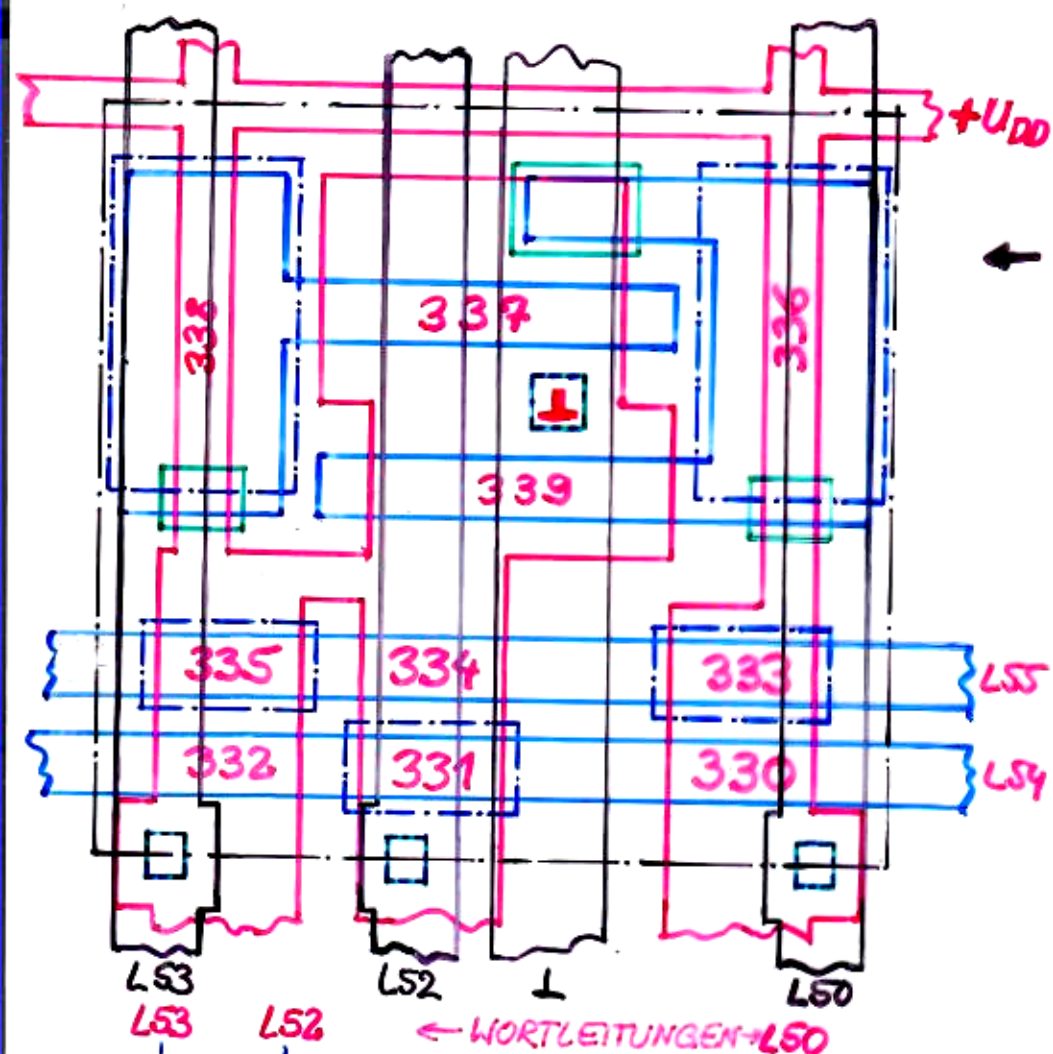
$$t_{90}/\text{ns} \approx 65 \frac{C_L/\text{pF}}{(\frac{b}{L})_{\text{last}}}$$

③ $J \sim U$ (ohmsche Last; Enh. Last mit $U_{GS} \gg U_{DD}$)
(praktisch nicht)

④ $J \sim U^2$ (Enhanc. Last)

$$t_{90}/\text{ns} \approx 280 \frac{C_L/\text{pF}}{(\frac{b}{L})_{\text{last}}}$$

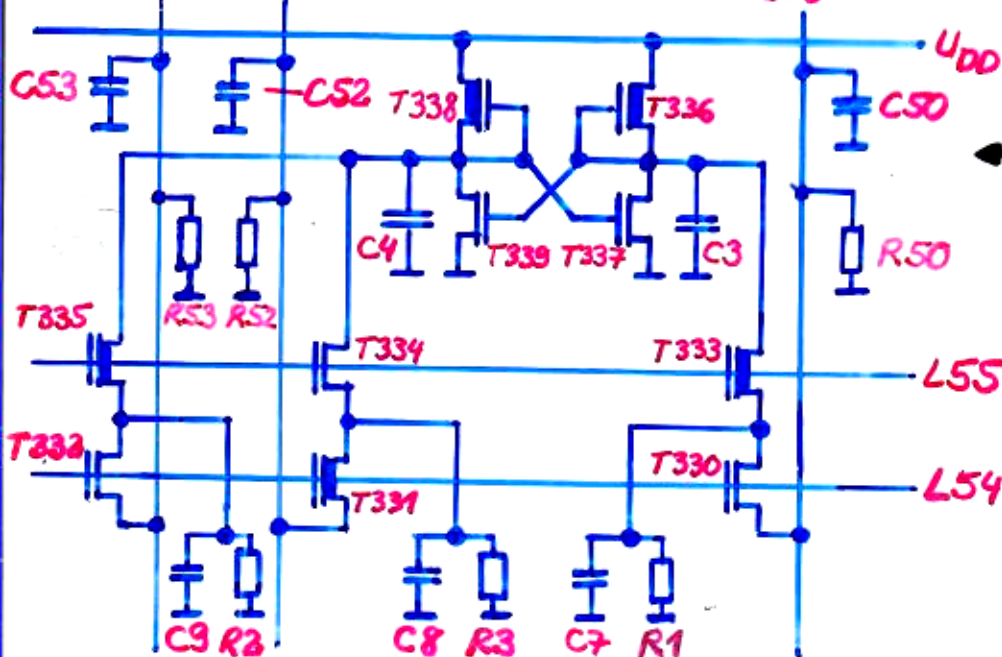




← Layoutentwurf auf
Millimeterpapier oder
K-folie
Maßstab 1000:1

Tr.	b/L	C	AP
330	4	C3	0,3
331	4	C4	0,34
332	4	C7	0,024
333	4	C8	0,024
334	4	C9	0,024
335	4	C50	
336	10	C52	0,364 AU
337	10	C53	
338	10		
339	10		

alle R: 10



← Simulationsmodell (NWA)
der Speicherzelle

Adr.eingänge

STADNET-BEISPIEL